

# Search Notes



Application/Control No.

09/767,730

Examiner

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Applicant(s)/Patent under Reexamination

BUCKLEY ET AL.

Art Unit

3629

## SEARCHED

Class	Subclass	Date	Examiner
705	1	10/05	DN
	5		
	6		
	7		
	8		
	9		
	10		
	26		
706	45		

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
I US patent PGPub	10/05	DN
II Foreign epo spo Derwent		
III NPL Dialog		
Review parent RCE	10/05	DN